

## Microstructure and recording mechanism of Bi–Fe–(N) layer for high-density write-once optical disk

Hung-Chuan Mai, Tsung-Eong Hsieh, Shiang-Yao Jeng, Chong-Ming Chen, and Jen-Long Wang

Citation: *Applied Physics Letters* **92**, 021906 (2008); doi: 10.1063/1.2828335

View online: <http://dx.doi.org/10.1063/1.2828335>

View Table of Contents: <http://scitation.aip.org/content/aip/journal/apl/92/2?ver=pdfcov>

Published by the [AIP Publishing](#)

---

### Articles you may be interested in

Microstructure and mechanical properties of Ti–B–C–N–Si nanocomposite films deposited by unbalanced magnetron sputtering

*J. Vac. Sci. Technol. A* **31**, 061401 (2013); 10.1116/1.4815952

Characterization of write-once blu-ray disk containing Cu–Al/Si recording layer using transmission electron microscopy

*Appl. Phys. Lett.* **98**, 094103 (2011); 10.1063/1.3560053

Microstructure and ferroic properties of epitaxial [  $\text{Fe}_2\text{O}_3$  –  $\text{BiFeO}_3$  ]  $\text{Bi}_{3.25}\text{La}_{0.75}\text{Ti}_3\text{O}_{12}$  composite bilayers

*J. Appl. Phys.* **108**, 114111 (2010); 10.1063/1.3514591

Magnetic field dependent critical current density of Bi–Sr–Ca–Cu–O superconductor in bulk and tape form with addition of  $\text{Fe}_3\text{O}_4$  magnetic nanoparticles

*J. Appl. Phys.* **105**, 07E311 (2009); 10.1063/1.3070628

Microstructure and recording mechanism of Ge / Au bilayer media for write-once optical disc

*Appl. Phys. Lett.* **90**, 151111 (2007); 10.1063/1.2721844

---

The advertisement features a dark blue background with white and orange text. At the top left, it reads 'NEW! Asylum Research MFP-3D Infinity™ AFM' in large white letters, followed by 'Unmatched Performance, Versatility and Support' in orange. On the right, the Oxford Instruments logo is shown with the tagline 'The Business of Science®'. Below the text are four images: a textured surface, a circular pattern, a grid of small squares, and the MFP-3D Infinity AFM instrument itself. Text descriptions are placed around these images: 'Stunning high performance' next to the textured surface, 'Simpler than ever to GetStarted™' next to the circular pattern, 'Comprehensive tools for nanomechanics' next to the grid, and 'Widest range of accessories for materials science and bioscience' next to the AFM instrument.

## Microstructure and recording mechanism of Bi-Fe-(N) layer for high-density write-once optical disk

Hung-Chuan Mai and Tsung-Eong Hsieh<sup>a)</sup>

Department of Materials Science and Engineering, National Chiao Tung University, 1001 Ta-Hsueh Rd., Hsinchu, Taiwan 300, Republic of China

Shiang-Yao Jeng, Chong-Ming Chen, and Jen-Long Wang

Prodisc Technology, Inc., No.35, Wu-Kung 6th Rd., Wugu Shiang, Taipei, Taiwan 242, Republic of China

(Received 7 September 2007; accepted 26 November 2007; published online 17 January 2008)

Bi-Fe-(N) thin film as the recording layer of high density digital versatile disk recordable optical disk was developed. For the disk sample with optimized layer structure, maximum partial response signal to noise ratio of 21.1 and minimum simulated bit error rate of  $5 \times 10^{-7}$  were achieved at the write power=5.7 mW. Transmission electron microscopy characterization illustrated that the separation of Bi and Fe elements to form the coarse granular structure in the mark regime during laser irradiation comprised of the recording mechanism. © 2008 American Institute of Physics. [DOI: 10.1063/1.2828335]

Optical disks are the most important external storage devices for contemporary information management due to their large recording capacity, interchangeability, and portability.<sup>1,2</sup> A main development trend of optical disks is to increase the recording capacity as it can be seen from the evolution of compact disk<sup>3</sup> into digital versatile disks (DVDs).<sup>4</sup> Presently, high density DVD (HD DVD) and Blu-ray (BD-R) disks are recognized as the next-generation recording media.<sup>5</sup>

For write-once disks, various organic and inorganic recording materials have been proposed.<sup>6</sup> Inorganic-type materials include phase-change alloys,<sup>7</sup> single-layer AlSi alloys,<sup>8</sup> bilayer metals such as Cu/Si,<sup>9</sup> Zn/Ge,<sup>10</sup> Ge/Au,<sup>11</sup> Cu/a-Si,<sup>12</sup> etc. Among these, Bi-related alloys such as Bi-Ge alloy<sup>13,14</sup> and Bi oxide (BiFeO)<sup>15,16</sup> exhibit promising applications for write-once data storage. For Bi-Ge-(N) alloy, the recording mechanism was attributed to the reflectivity change caused by the decomposition of Bi nitride in the recording layer as well as the deformation in recording marks due to the gas release.<sup>14</sup> As to the BiFeO, the signal recording was resulted from the crystallization of Bi and BiO.<sup>16</sup>

This work studies the feasibility of Bi-Fe-(N) recording layer to HD DVD recordable (DVD-R) optical disks and the recording mechanism. Optical disk samples were prepared in accord with HD-DVD specifications<sup>17</sup> via sputtering process. The multilayer disk structure is PC substrate/Ag (100 nm)/ZnS-SiO<sub>2</sub> (23 nm)/Bi-Fe(N) (10 nm)/ZnS-SiO<sub>2</sub> (40 nm)/PC substrate. The Bi-Fe-(N) layer was deposited by the sputtering of Bi-Fe alloy target under Ar/N<sub>2</sub> gas flow at the working pressure about 2 mtorr. The x-ray photoelectron spectroscopy (XPS) (ULVAC-PHI) revealed the average composition of Bi-Fe-(N) layer as Bi:Fe:N ≈ 40:57:3 (in at. %). Dynamic tester (ODU-1000, PULSTEC) equipped with a 405 nm laser diode and a numerical aperture of 0.65 was adopted to evaluate the optimum write power ( $P_w$ ) and signal properties of disk samples at the conditions of clock frequency=64.8 MHz, linear speed=6.61 m/s and the track pitch=0.4 μm.

Figure 1 plots the partial response signal to noise ratio (PRSNR) and simulated bit error rate (sbER) as a function of  $P_w$  of disk samples deduced by dynamic test. In addition to the good sensitivity of Bi-Fe-(N) disk sample at low  $P_w$ , the optimized disk sample achieved the maximum PRSNR of 21.1 and the minimum sbER of  $5 \times 10^{-7}$  at  $P_w$ =5.7 mW, as shown in Fig. 1, exceeding the requirements of HD-DVD specifications.<sup>17</sup> The eye pattern corresponding to the signals ranging from 2 to 11 T read directly from oscilloscope is shown in Fig. 2. The distinct signal tones evidence the random signals could be written perfectly in Bi-Fe-(N) disk samples.

Figure 3 presents the micrograph of signal marks in a recorded disk sample taken by transmission electron microscopy (TEM) (Jeol FX-II 2010).<sup>18</sup> Distinct, seashell-like signal marks with various recording lengths can be seen. Selected area electron diffraction (SAED) patterns taken from the nonmark and mark areas both exhibit the vague ring patterns, indicating that the Bi-Fe-(N) layer remains amorphous prior and posterior to laser writing. This is opposite to conventional disks in which the recording mechanism always

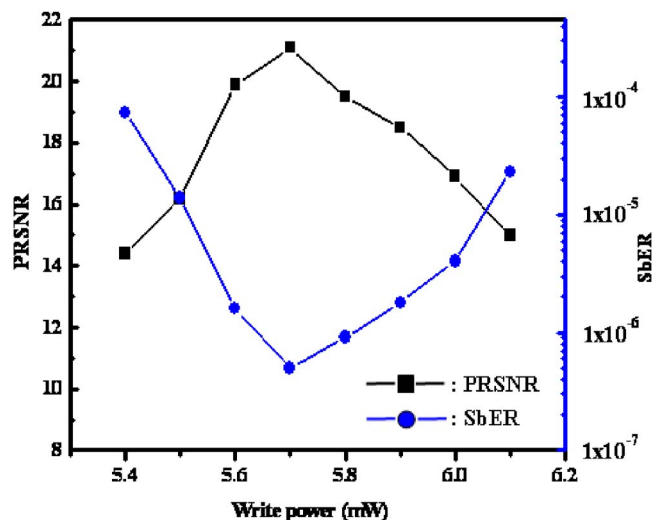


FIG. 1. (Color online) Variation of PRSNR and sbER of disk samples vs the write power ( $P_w$ ).

<sup>a)</sup> Author to whom correspondence should be addressed. Electronic mail: tehsieh@mail.nctu.edu.tw.

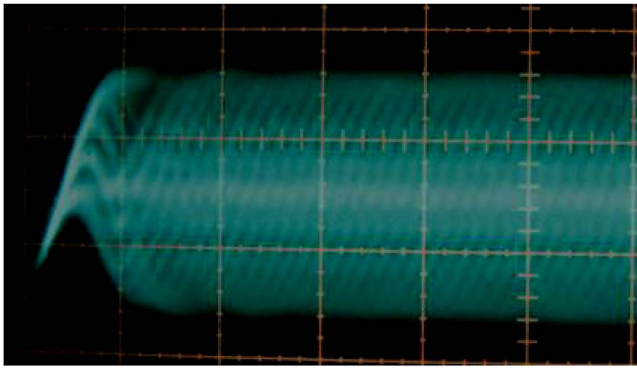


FIG. 2. (Color online) Eye patterns of random signals read directly from oscilloscope.

relies on the amorphous-to-crystalline phase transitions.

Figure 4 presents the variations of chemical compositions in a signal mark and its vicinity deduced by energy dispersive spectroscopy (EDS) (Link ISIS 300). Outside of the mark, the Bi and Fe elements are uniformly distributed while inside the mark, the Bi and Fe element distributions vary irregularly. This implies a distinct element separation in the Bi-Fe-(N) layer subjected to laser irradiation. The Bi-Fe binary alloy phase diagram indicates the room-temperature solid solubility of Fe in Bi is rather small and the Bi is nearly insoluble in Fe.<sup>19</sup> According to above TEM/EDS analysis, it was speculated that the laser thermal energy causes the element separation in the molten Bi-Fe and then, at the completion of signal recording, the fast quenching rate results in the formation of amorphous, irregular Bi-rich and Fe-rich solid solution phases. The element separation in conjunction with the coalescence/coarsening of separated phases consequently provided sufficient optical property change for signal readout in Bi-Fe-(N) disk samples.

Figure 5 shows the TEM micrograph of as-deposited Bi-Fe layer. The attached SAED pattern illustrates the

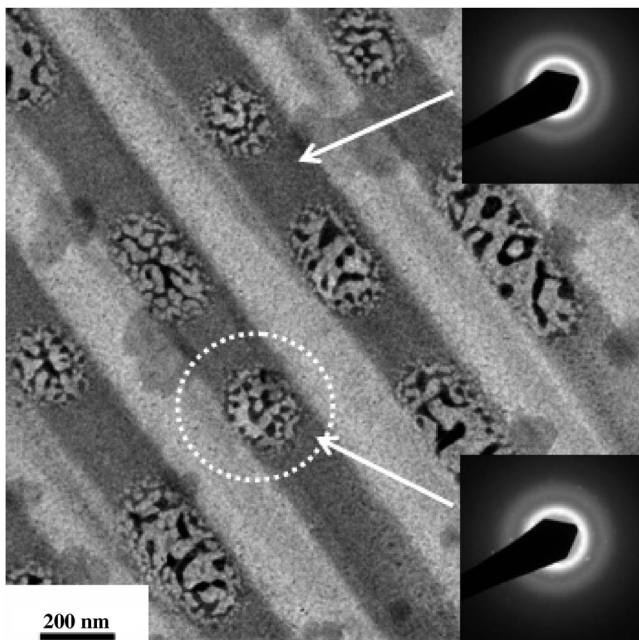


FIG. 3. TEM image of recording marks in an optical disk sample. The SAED patterns attached on upper and lower right-hand corners of TEM image were taken from the nonmark and mark areas, respectively.

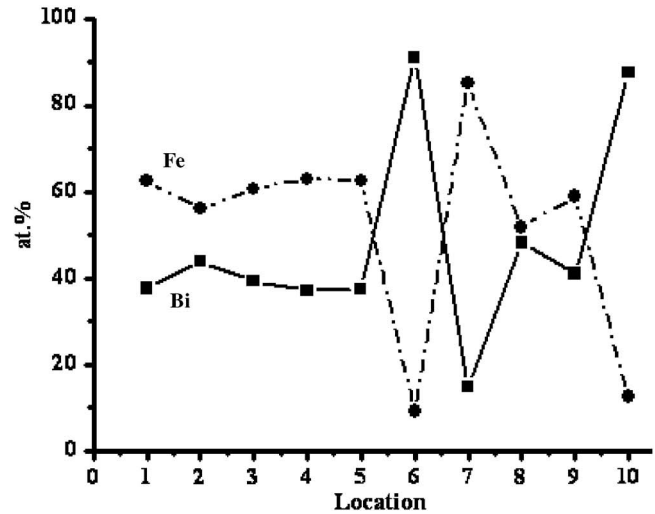
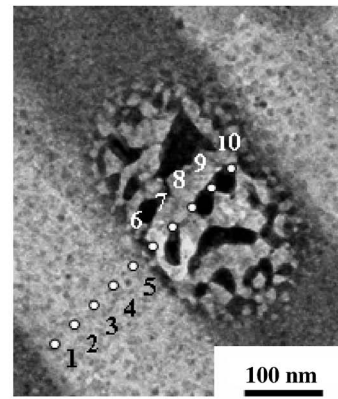


FIG. 4. Variations of chemical compositions deduced from the EDS analysis in the mark and its vicinity. Locations of EDS analysis are specified in inserted TEM micrograph.

nitrogen-free film is polycrystalline. Dark, coarse grains within the sizes of 50–70 nm embedded in fine grains within the sizes of 10–20 nm can be readily seen. EDS analysis revealed the coarse grains are Bi-rich (Fe content <14 at. %)

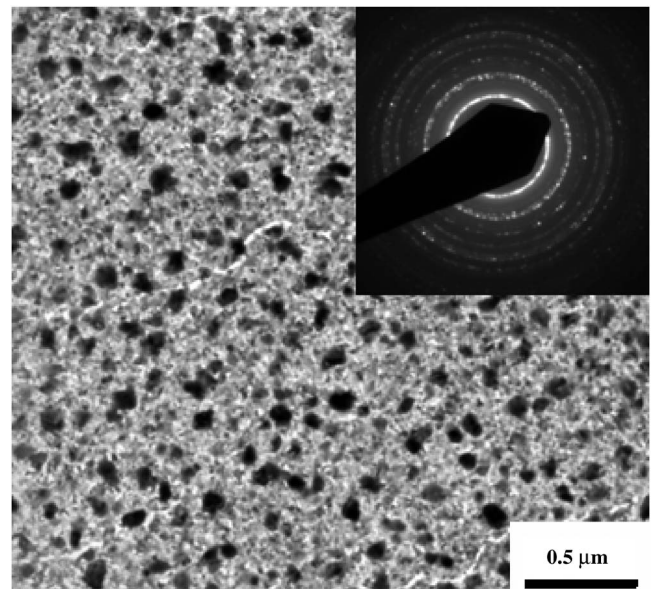


FIG. 5. TEM micrograph of as-deposited Bi-Fe layer. The attached SAED pattern indicates that the film is polycrystalline and dark, coarse grains are Bi-rich phase as revealed by EDS analysis.



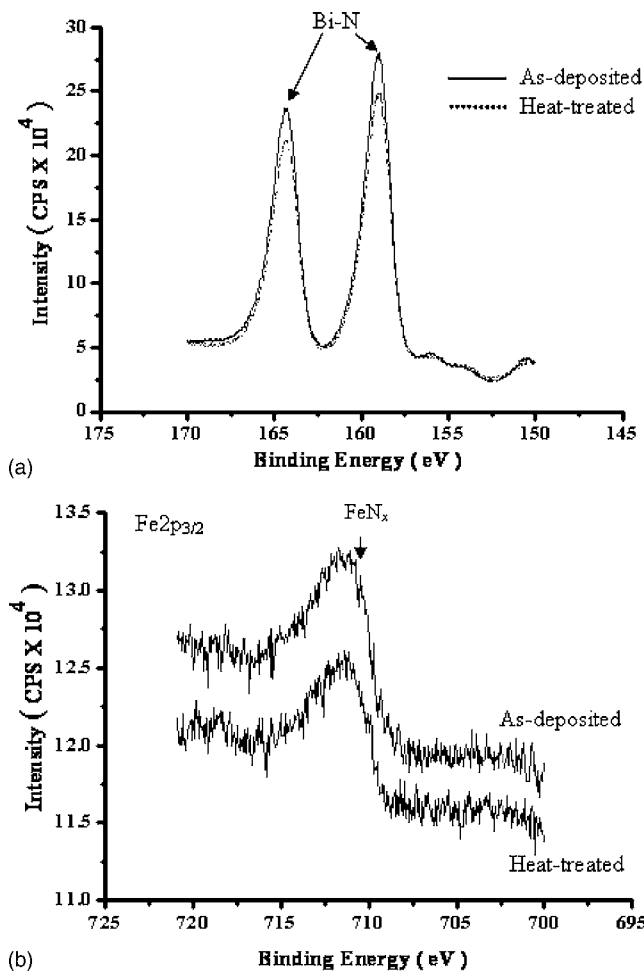


FIG. 6. XPS peaks of (a) Bi-N and (b) Fe-N bonds in an as-deposited and a Bi-Fe-(N) layer subjected to a rapid heating to 400 °C.

phase and the fine grains are mixed phases with average composition as Bi:Fe  $\approx$  2:3 (in at. %). Signal properties of disk samples containing Bi-Fe recording layer were evaluated by dynamic tester; nevertheless, none of them satisfied the HD DVD-R specifications. Though the shell-like marks could form in recorded disk, they were embedded in a coarse polycrystalline structure. The structure discrepancy of mark and nonmark areas in Bi-Fe disk samples is hence unable to induce sufficient optical property change for signal readout. This evidences that the introduction of nitrogen gas during the sputtering deposition of recording layer is essential in producing a fine, amorphous background structure in Bi-Fe-(N) disk samples. It exaggerates the optical property change of mark and nonmark areas and hence results in satisfactory signal properties of optical disks.

In order to further clarify above arguments, the Bi-Fe-(N) layer was heated at a rate about 100 °C/min to 400 °C, cooled down immediately in nitrogen ambient, and then transferred to XPS for analysis. The Bi-N (Ref. 14) and Fe-N (Ref. 20) bonds were identified, as revealed by the XPS spectra shown in Figs. 6(a) and 6(b). The introduction of nitrogen gas during sputtering results in the formation of those nitrides and they effectively induce the structure refinement in the Bi-Fe-(N) layer. The nitrides also inhibit the long-range ordering of atoms during signal writing and imply the amorphism of recorded marks. It is noted that Bi element signal is absent in the XPS peaks shown in Fig. 6(a), indicating the Bi-N nitride does not decompose during laser

writing. We evaluated the surface morphology of a recorded disk samples by an atomic force microscope (Nano Scope Dimension 3100) and found no periodic bulge up on the disk surface. Hence, the formation of nitrogen gas bubbles caused by the decomposition of nitrides in recorded marks was expelled from the recording mechanism of Bi-Fe-(N) disk samples.<sup>14,21,22</sup>

In summary, we demonstrate the feasibility of Bi-Fe-(N) layer as the recording media in HD DVD-R optical disks. PRSNR of 21.1 and sBER of  $5 \times 10^{-7}$  were achieved at  $P_w = 5.7$  mW in the optimized disk sample. TEM/EDS characterization revealed the coarse Bi- and Fe-rich solid solution phases comprise of the signal marks in disk samples. A notable feature in the Bi-Fe-(N) disk samples is the mark area remains amorphous after signal recording. The optical property change of Bi-Fe-(N) recording layer required for signal readout was resulted from the distinct grain size change and element separation, rather than the amorphous-to-crystalline structure change as in conventional optical disks. Nitride decomposition and nitrogen gas release in recording layer were not ascribed to the recording mechanism of Bi-Fe-(N) optical disk samples.

The authors acknowledge the financial support by National Science Council (NSC), Taiwan, ROC, under Contract No. NSC95-2221-E090-130.

<sup>1</sup>M. Takenaga, N. Yamada, K. Nishiuchi, N. Akahira, T. Ohta, S. Nakamura, and T. Yamashita, *J. Appl. Phys.* **54**, 5376 (1983).

<sup>2</sup>Y. Unno and K. Goto, *Proc. SPIE* **382**, 32 (1983).

<sup>3</sup>B. Tieke, G. R. Langereis, E. R. Meinders, J. G. F. Kablau, R. Woudenberg, and R. A. J. van Kollenburg, *Jpn. J. Appl. Phys., Part 1* **41**, 1735 (2002).

<sup>4</sup>K. Nishiuchi, H. Kitaura, N. Yamada, and N. Akahira, *Jpn. J. Appl. Phys., Part 1* **37**, 2163 (1998).

<sup>5</sup>R. J. M. Vullers, A. E. T. Kuiper, and D. Pasquariello, *Jpn. J. Appl. Phys., Part 1* **45**, 1219 (2006).

<sup>6</sup>A. E. T. Kuiper and L. van Pieterse, *MRS Bull.* **31**, 308 (2006).

<sup>7</sup>N. Ishii, N. Kinoshita, N. Shimidzu, H. Tokumaru, H. Okuda, A. Hirotsune, Y. Anzai, M. Terao, and T. Maeda, *Jpn. J. Appl. Phys., Part 1* **41**, 1691 (2002).

<sup>8</sup>B. M. Chen and R. L. Yeh, *Proc. SPIE* **5380**, 141 (2004).

<sup>9</sup>A. E. T. Kuiper, R. J. M. Vullers, D. Pasquariello, and E. P. Naburgh, *Appl. Phys. Lett.* **86**, 221921 (2005).

<sup>10</sup>C. P. Liu, J. S. Tsai, G. J. Huang, Y. T. Hung, T. R. Jeng, J. J. Ju, and D. R. Huang, *Asia-Pacific Data Storage Conference*, Hsinchu, Taiwan, 2006 (unpublished), p. 172.

<sup>11</sup>T. H. Wu, P. C. Kuo, Y. H. Fang, J. P. Chen, P. F. Yen, T. R. Jeng, C. Y. Wu, and D. R. Huang, *Appl. Phys. Lett.* **90**, 151111 (2007).

<sup>12</sup>Y. C. Her and C. L. Wu, *Jpn. J. Appl. Phys., Part 1* **43**, 1013 (2004).

<sup>13</sup>Y. Hosoda, T. Izumi, A. Mitsumori, F. Yokogawa, S. Jinno, and H. Kudo, *Jpn. J. Appl. Phys., Part 1* **42**, 1040 (2003).

<sup>14</sup>Y. Hosoda, A. Mitsumori, M. Sato, and M. Yamaguchi, *Jpn. J. Appl. Phys., Part 1* **43**, 4997 (2004).

<sup>15</sup>N. Sasa, Y. Hayashi, T. Fujii, K. Otaka, A. Watada, H. Kamezaki, and H. Komoda, *Jpn. J. Appl. Phys., Part 1* **43**, 4972 (2004).

<sup>16</sup>N. Sasa, Y. Hayashi, T. Fujii, A. Watada, and H. Komoda, *Jpn. J. Appl. Phys., Part 1* **44**, 3643 (2005).

<sup>17</sup>DVD specifications for high-density recordable disk (HD DVD-R) for blue laser optical system, Version 0.9, The DVD Forum, July 2004.

<sup>18</sup>H. W. Chen, T. E. Hsieh, J. R. Liu, and H. P. D. Shieh, *Jpn. J. Appl. Phys., Part 1* **38**, 1691 (1999).

<sup>19</sup>T. B. Massalski, J. L. Murray, L. H. Bennett, and H. Baker, *Binary Alloy Phase Diagrams*, 1st ed. (American Society for Metals, Metals Park, Ohio, 1986), Vol. 1, p. 502.

<sup>20</sup>M. K. Lei and X. M. Zhu, *J. Electrochem. Soc.* **152**, B291 (2005).

<sup>21</sup>J. Tominaga, S. Haratani, K. Uchiyama, and S. Takayama, *Jpn. J. Appl. Phys., Part 1* **31**, 2757 (1992).

<sup>22</sup>H. L. Chang, T. R. Jeng, J. P. Chen, W. H. Yen, P. Yen, D. Huang, and J. J. Ju, *Jpn. J. Appl. Phys., Part 1* **44**, 6109 (2005).